AMENDMENTS TO THE CLAIMS

Please cancel claims 1-42 and 57-81 and amend claims 43 and 50 according to the following listing of claims:

1-42. (cancelled)

43. (currently amended) A process for preparing a p-n junction having a p-type ZnO film and an n-type film wherein the net acceptor concentration is at least about 10¹⁵ acceptors/cm³, the process comprising:

cleaning a substrate;

adjusting the temperature of the substrate in \underline{a} the pulsed laser deposition chamber to between about 200°C to about 1000°C;

growing a p-type ZnO film on the substrate by directing an excimer pulsed laser beam onto a pressed ZnO powder pellet containing a p-type dopant element to grow a p-type ZnO film containing at least about 10^{15} 10^{18} acceptors/cm³ on the substrate; and

growing an n-type film on top of the p-type ZnO film by directing an excimer pulsed laser beam onto a pressed powder pellet containing an n-type dopant element to grow an n-type film on the p-type ZnO film on the substrate.

- 44. (original) The process as set forth in claim 43 wherein the n-type film has a thickness of between about 0.5 and about 3 micrometers and the p-type film has a thickness of between about 0.5 and about 3 micrometers.
- 45. (original) The process as set forth in claim 43 wherein the p-type dopant element is arsenic and the n-type dopant element is aluminum.
- 46. (original) The process as set forth in claim 43 wherein the p-n junction is a homoepitaxial p-n junction

wherein the p-type film consists of arsenic and ZnO and the n-type film consists of an n-type dopant element and ZnO.

- 47. (original) The process as set forth in claim 43 wherein the p-n junction is a heteroepitaxial p-n junction wherein the p-type film consists of arsenic and ZnO and the n-type film contains an n-type dopant and has an energy band gap different than ZnO.
 - 48. (original) The process as set forth in claim 43 wherein the substrate is cleaned in the pulsed laser deposition chamber using a pulsed excimer laser.
 - 49. (original) The process as set forth in claim 43 wherein the net acceptor concentration is at least about 10^{16} acceptors/cm³.
 - 50. (currently amended) A process for preparing a p-n junction having a p-type ZnO film and an n-type film wherein the net acceptor concentration is at least about 10¹⁵ acceptors/cm³, the process comprising:

cleaning a substrate;

adjusting the temperature of the substrate in a the pulsed laser deposition chamber to between about 200°C to about 1000°C;

growing an n-type film on top of the substrate by directing an excimer pulsed laser beam onto a pressed powder pellet containing an n-type dopant element to grow an n-type film on the substrate;

growing a p-type ZnO film on the n-type film by directing an excimer pulsed laser beam onto a pressed ZnO powder pellet containing a p-type dopant element to grow a p-type ZnO film containing at least about 10^{15} 10^{18} acceptors/cm³ on the n-type film.

51. (original) The process as set forth in claim 50 wherein the n-type film has a thickness of between about 0.5

and about 3 micrometers and the p-type film has a thickness of between about 0.5 and about 3 micrometers.

- 52. (original) The process as set forth in claim 50 wherein the p-type dopant element is arsenic and the n-type dopant element is aluminum.
- 53. (original) The process as set forth in claim 50 wherein the p-n junction is a homoepitaxial p-n junction wherein the p-type film consists of arsenic and ZnO and the n-type film consists of an n-type dopant element and ZnO.
- 54. (original) The process as set forth in claim 50 wherein the p-n junction is a heteroepitaxial p-n junction wherein the p-type film consists of arsenic and ZnO and the n-type film contains an n-type dopant and has an energy band gap different than ZnO.
- 55. (original) The process as set forth in claim 50 wherein the substrate is cleaned in the pulsed laser deposition chamber using a pulsed excimer laser.
- 56. (original) The process as set forth in claim 50 wherein the net acceptor concentration is at least about 10^{16} acceptors/cm³.

57-81. (cancelled)